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-213202.00354

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

MAPE Application of:

Examiner: NYA

James SAMSOONDAR

Group Art Unit: 1743

PATENT APPLICAT

Application No.: 10/023,869

Filed: December 21, 2001

For: QUALITY CONTROL MATERIAL

FOR REAGENTLESS MEASUREMENT:

OF ANALYTES

December 20, 2002

Commissioner for Patents Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

RECEIVED
DEC 2 3 2002
TC 1700

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed documents are provided.

In accordance with 37 CFR 1.97(h), this Information Disclosure Statement is not to be construed as an admission that the information cited is, or is considered to be, material to the patentability as defined in 37 CFR 1.56(b).

Each item of information contained in this Information Disclosure

Statement is being submitted prior to the mailing of an Office Action on the merits.

Accordingly, no fee is believed due for consideration of this Information Disclosure



CONCLUSION

It is respectfully requested that the below-listed information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicant's undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 625-3500. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

Attorney for Applicant

Dawn C. Hayes

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Patent Administrator
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FORM PTO 1449 (n	modified)		ATTY DOCKET NO.		APPLICATION N	APPLICATION NO.		
U.S. DEPARTMENT OF COMMERCE			213202.00354 10/023,869					
PATENT AND TRADEMARK OFFICE			APPLICANT					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			James SAMSOONDAR					
			FILING DATE			GROUP		
December 20, 2	2002		December 21, 2001			1743		
		U.S	S. PATENT DOCUMENTS				# 1	
*EXAMINER	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
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DEC 2 0 2002	(C)						·	
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FOREIGN PATENT DOCUMENTS TRANSLATION								
	DOCUMENT NUMBER	DATE	C	OUNTRY	CLASS	SUBCLASS	YES/NO/ OR ABSTRACT	
	OTHER DO	CUMENT(S) (Inc	Jüding A	uthor, Title, Date, Pert	inentiPages, Etc.)	I IFD SPECTROS	SCOPY Vol. 52	
	Ozdemir, et al., "Hybrid Calibration Models: An alternative to Calibration Transfer" APPLIED SPECTROSCOPY, Vol. 52, No. 4 (1998) pp 599-603							
	Bouveresse, E., et al., effects of different sta	Bouveresse, E., et al., "Calibration transfer across near-infrared spectrometric instruments using Shenk's algorithm: effects of different standarisation samples" ANALYTICA CHIMICA ACTA, 297 (1994) pp. 405-416						
		Blank, et al., "Transfer of Near-Infrared Multivariate Calibrations without Standards" ANALYTICAL CHEMISTRY, Vol. 68, No. 17 (1996) pp. 2987-2995 /						
		Blanco, et al., "Wavelength Calibration Transfer between Diode Array UV-Visible Spectrophotometers" <u>APPLIED</u> <u>SPECTROSCOPY</u> , Volume 49, No. 5 (1995) pp. 593-597						
		Wang, et al., "Multivariate Instrument Standardization" <u>ANALYTICAL CHEMISTRY</u> , Vol. 63, No. 23 (1991) pp. 2750-2756						
	Gemperline, et al., "Appearance of Discontinuities in Spectra Transformed by the Piecewise Direct Instrument Standardization Procedure" <u>ANALYTICAL CHEMISTRY</u> , Vol. 68, No. 17 (1996) pp. 2913-2915							
EXAMINER			Di	DATE CONSIDERED				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet <u>1</u> of <u>1</u>

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